IN THE CLAIMS:

- 1. For collecting a specimen of a substance, a sampler, comprising:
- a sampler body;
- a plunger slidably contained within the sampler body and having an actuating end;
- a platen having first and second opposing sides, the first side being removably couplable to an end of the sampler body plunger opposite the actuating end;
- a spring cooperatively coupled to the plunger and located between the platen and the actuating end and being configured to retract the platen within the sampler body; and

a sampling medium coupleable to the second side and configured to retain a specimen of a substance thereon.

- 2. (Currently Amended) The sampler as recited in Claim 1 further comprising a plunger slidably coupled tot the sampler body and configured to removably couple to the platen wherein the spring is configured to project at least a portion of the platen outside the sampler body when the actuating end is depressed and retract the platen within the sampler body when the actuating end is released.
- 3. (Original) The sampler as recited in Claim 1 wherein the sampling medium comprises a foil of silver, carbon, indium, copper, or gold.
- 4. (Original) The sampler as recited in Claim 1 further comprising a platen cap configured to removably couple to the sampler body proximate the platen.

- 5. (Currently Amended) The sampler as recited in Claim 1 further comprising a rotatable platen coupled to the sampler body and configured to selectably selectively expose the sampling medium.
- 6. (Original) The sampler as recited in Claim 1 further comprising a specimen cap coupled to the platen.
 - 7. (Canceled) The sampler as recited in Claim 1 further comprising
- 8. (Original) The sampler as recited in Claim 1 further comprising a security cap removably coupleable to the sampler body distal the platen.
- 9. (Original) The sampler as recited in Claim 1 wherein the platen is configured to couple to an analytical tool.
- 10. (Original) The sampler as recited in Claim 9 wherein the analytical tool is selected from the group consisting of:
 - a scanning electron microscope;
 - an Auger electron microscope;
 - a focused ion beam tool; and
 - an X-ray reflection diffractometer.

11. (Currently Amended) A method of manufacturing a sampler for collecting a specimen of a substance on a surface, comprising:

coupling a sampler body to a platen having first and second opposing sides at the first side; and

coupling a sampling medium to the second side, the sampling medium configured to retain a specimen of a substance thereon.

providing a sampler body;

slidably positing a plunger within the sampler body, the plunger having an actuating end;

removably coupling a first side of a platen to the plunger to an end of the plunger opposite

the actuating end;

cooperatively coupling a spring to the plunger between the platen and the actuating end, the spring being configured to retract the platen within the sampler body; and

coupling a sampling medium to a second side opposing the first side and being configured to retain a specimen of a substance thereon.

12. (Currently Amended) The method as recited in Claim 11 further comprising slidably coupling a plunger to the sampler body, the plunger configured to removably couple to the platen wherein cooperatively coupling the spring includes coupling the spring to project at least a portion of the platen outside the sampler body when the actuating end is depressed and retract the platen within the sampler body when the actuating end is released.

- 13. (Original) The method as recited in Claim 11 wherein coupling a sampling medium includes coupling a sampling medium comprising a foil of silver, carbon, indium, copper, or gold.
- 14. (Original) The method as recited in Claim 11 further comprising coupling a platen cap to the sampler body proximate the platen, the platen cap configured to removably cover the platen.
- 15. (Currently Amended) The method as recited in Claim 11 further comprising coupling a rotatable platen to the sampler body, the rotatable platen configured to selectably selectively expose the sampling medium.
- 16. (Original) The method as recited in Claim 11 further comprising coupling a specimen cap to the platen.
 - 17. (Canceled)
- 18. (Original) The method as recited in Claim 11 further comprising coupling a security cap to the sampler body distal the platen.
- 19. (Original) The method as recited in Claim 11 wherein coupling a platen includes coupling a platen configured to couple to an analytical tool.

- 20. (Original) The method as recited in Claim 19 wherein coupling a platen includes coupling a platen configured to couple to an analytical tool selected from the group consisting of:
 - a scanning electron microscope;
 - an Auger electron microscope;
 - a focused ion beam tool; and
 - an X-ray reflection diffractometer.